



CERTIFICATE OF ACCREDITATION

The ANSI National Accreditation Board

Hereby attests that

Accura Calibration
2834 West Kingsley Road
Garland, TX 75041

Fulfills the requirements of

ISO/IEC 17025:2017

and national standards

ANSI/NCSL Z540-1-1994 (R2002) AND
ANSI/NCSL Z540.3-2006 (R2013)

In the field of

CALIBRATION

This certificate is valid only when accompanied by a current scope of accreditation document.
The current scope of accreditation can be verified at www.anab.org.

Jason Stine, Vice President

Expiry Date: 01 February 2026
Certificate Number: AC-2548



This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2017.
This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory
quality management system (refer to joint ISO-ILAC-IAF Communiqué dated April 2017).

SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017

AND

ANSI/NCSL Z540-1-1994 (R2002)

ANSI/NCSL Z540.3-2006 (R2013)

Accura Calibration
2834 West Kingsley Road
Garland, TX 75041
Dwight Martin 972-278-7878

CALIBRATION

Valid to: **February 1, 2026**

Certificate Number: **AC-2548**

Acoustics and Vibration

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Accelerometers Frequency Response (1 g Reference)	(7 to 10) Hz (10 to 30) Hz (30 to 99) Hz 100 Hz (101 to 2 000) Hz (2 000 to 10 000) Hz	7 % of reading 4.6 % of reading 3.8 % of reading 3.8 % of reading 3.8 % of reading 5.3 % of reading	Comparisons to Modal Shop 9110D Workstation
Sound Level – Generate (Measuring Equipment)	1 kHz (94 to 114) dB	0.23 dB	Comparison to B&K 4231 Sound Level Calibrator
Sound Level – Measure Class 1 Sound Level Meter	1 kHz (94 to 114) dB	1 dB	Comparison to Sound Level Meter characterized with B&K 4231 Sound Level Meter
Sound Level – Measure Class 2 Sound Level Meter	1 kHz (94 to 114) dB	2 dB	Comparison to Sound Level Meter characterized with B&K 4231 Sound Level Meter

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
AC Current – Clamp Meter ¹ Toroidal Clamp	(45 to 65) Hz (20 to 300) A (300 to 600) A (600 to 1 000) A 400 Hz (20 to 300) A (300 to 600) A 200 Hz (600 to 1 000) A	11 mA/A + 90 mA 9.8 mA/A + 90 mA 11 mA/A + 90 mA 19 mA/A + 0.1 A 18 mA/A + 0.1 A 18 mA/A + 0.1 A	Comparison to Fluke 5500A/Coil, Valhalla 2575A Current Shunt, Keysight 3458A 8.5 Digit Multimeter, Current Source
AC Current – Clamp Meter ¹ Toroidal Clamp	(45 to 400) Hz (495 to 1 401) A	0.3 A	Comparison to Transmille 4010A Multiproduct Calibrator, Transmille EA002 2/10/50 Coil Adapter
AC Current – Clamp Meter ¹ Non-Toroidal Clamp	(45 to 65) Hz (20 to 300) A (300 to 600) A (600 to 1 000) A 400 Hz (20 to 300) A (300 to 600) A 200 Hz (600 to 1 000) A	15 mA/A + 0.9 A 14 mA/A + 0.9 A 14 mA/A + 0.9 A 22 mA/A + 0.9 A 21 mA/A + 0.9 A 22 mA/A + 0.9 A	Comparison to Fluke 5500A/Coil, Valhalla 2575A Current Shunt, Keysight 3458A 8.5 Digit Multimeter, Current Source
AC Current – Clamp Meter ¹ Non-Toroidal Clamp	(45 to 400) Hz (495 to 1 401) A	0.3 A	Comparison to Transmille 4010A Multiproduct Calibrator, Transmille EA002 2/10/50 Coil Adapter
DC Voltage – Source ¹ (Locked Ranges)	(0 to 329.999 9) mV (0 to 3.299 999) V (0 to 32.999 99) V (30 to 329.999 9) V (100 to 1 020) V	16 μ V/V + 0.78 μ V 9.1 μ V/V + 1.6 μ V 9.7 μ V/V + 16 μ V 14 μ V/V + 0.12 μ V 15 μ V/V + 1.2 μ V	Comparison to Fluke Multiproduct Calibrator
DC Voltage – Source (Fixed Artifact)	100 mV 1 V 10 V 100 V 1 000 V	50 μ V/V 2.1 μ V/V 2 μ V/V 2 μ V/V 2 μ V/V	Comparison to Fluke 732B DC Voltage Reference Standard

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
DC Voltage – Measure ¹	Up to 120 mV (0.12 to 1.2) V (1.2 to 12) V (12 to 120) V (120 to 1 050) V	6.1 $\mu\text{V/V} + 0.3 \mu\text{V}$ 5.1 $\mu\text{V/V} + 0.3 \mu\text{V}$ 5.1 $\mu\text{V/V} + 0.5 \mu\text{V}$ 7.3 $\mu\text{V/V} + 30 \mu\text{V}$ 7.3 $\mu\text{V/V} + 0.1 \text{ mV}$	Comparison to Keysight 3458A 8.5 Digit Multimeter
DC High Voltage – Source/Measure ¹	(1 to 60) kV	0.78 mV/V	Comparison to Ross Engineering VD60-6.2Y-A-LB-AL High Voltage Divider, Keysight 3458A 8.5 Digit Multimeter
DC Current – Source ¹	(0 to 202) μA (0.2 to 2.02) mA (2 to 20.2) mA (20 to 202) mA (0.2 to 2.02) A (2 to 20.2) A (20.2 to 30) A	6.1 $\mu\text{A/A} + 7.8 \text{ pA}$ 55 $\mu\text{A}/\mu\text{A} + 23 \text{ nA}$ 42 $\mu\text{A}/\mu\text{A} + 0.16 \mu\text{A}$ 42 $\mu\text{A}/\mu\text{A} + 1.6 \mu\text{A}$ 0.11 mA/A + 23 μA 0.25 mA/A + 0.23 μA 70 $\mu\text{A/A} + 0.35 \text{ mA}$	Comparison to Transmille 4010A Multiproduct Calibrator
DC Current – Source ¹	(> 30 to 100) A	12 mA/A	Comparison to Multiproduct Calibrator, Transconductance Amplifier monitored with Keysight 3458A 8.5 Digit Multimeter and Current Shunt
DC Current – Clamp Meter ¹	(10 to 1 400) A	0.46 % of reading + 0.42 A	Comparison to Transmille 4010A Multiproduct Calibrator, Transmille EA002 2/10/50 Coil Adapter
DC Current – Measure	(0 to 330) μA (> 0.33 to 3.3) mA (> 3.3 to 33) mA (> 33 to 330) mA (> 0.33 to 3) A (> 3 to 20.5) A	0.68 nA 5 nA 37 nA 1.4 μA 2.2 mA 22 mA	Comparison to Keysight 3458A 8.5 Digit Multimeter, Current Shunts, Standard Resistors
DC Current – Measure	(> 20.5 to 100) A	12 mA/A	Comparison to Keysight 3458A 8.5 Digit Multimeter, Current Shunt

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
AC Voltage – Source ¹	(1 to 32.999) mV (10 to 45) Hz	0.64 mV/V + 4.7 μ V	Comparison to Fluke 5522A Multiproduct Calibrator
	45 Hz to 10 kHz	0.15 mV/V + 4.7 μ V	
	(10 to 20) kHz	0.18 mV/V + 4.7 μ V	
	(20 to 50) kHz	0.79 mV/V + 4.7 μ V	
	(50 to 100) kHz	2.7 mV/V + 9.3 μ V	
	(100 to 500) kHz	6.4 mV/V + 39 μ V	
	(33 to 329.999) mV (10 to 45) Hz	0.36 mV/V + 6.2 μ V	
	45 Hz to 10 kHz	0.3 mV/V + 6.2 μ V	
	(10 to 20) kHz	0.3 mV/V + 6.2 μ V	
	(20 to 50) kHz	0.52 mV/V + 6.2 μ V	
	(50 to 100) kHz	0.97 mV/V + 27 μ V	
	(100 to 500) kHz	2.8 mV/V + 54 μ V	
	(0.33 to 3.299 99) V (10 to 45) Hz	0.23 mV/V + 39 μ V	
	45 Hz to 10 kHz	0.12 mV/V + 47 μ V	
	(10 to 20) kHz	0.15 mV/V + 47 μ V	
	(20 to 50) kHz	0.24 mV/V + 39 μ V	
	(50 to 100) kHz	0.55 mV/V + 97 μ V	
	(100 to 500) kHz	1.9 mV/V + 0.47 mV	
	(3.3 to 32.999 9) V (10 to 45) Hz	0.23 mV/V + 0.5 mV	
	45 Hz to 10 kHz	0.12 mV/V + 0.47 mV	
	(10 to 20) kHz	0.2 mV/V + 4.7 mV	
	(20 to 50) kHz	0.23 mV/V + 4.7 mV	
	(50 to 100) kHz	0.7 mV/V + 1.2 mV	
	(33 to 329.999) V 45 Hz to 1 kHz	0.15 mV/V + 1.6 mV	
	(1 to 10) kHz	0.16 mV/V + 4.7 mV	
	(10 to 20) kHz	0.2 mV/V + 4.7 mV	
	(20 to 50) kHz	0.25 mV/V + 4.7 mV	
	(50 to 100) kHz	0.7 mV/V + 39 mV	
	(330 to 1 020) V 45 Hz to 1 kHz	0.24 mV/V + 7.8 mV	
	(1 to 5) kHz	0.2 mV/V + 7.8 mV	
	(5 to 10) kHz	0.24 mV/V + 7.8 mV	

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
AC Voltage – Measure ¹	10 nV to 12 mV		Comparison to Keysight 3458A 8.5 Digit Multimeter
	(1 to 40) Hz	0.7 mV/V	
	40 Hz to 1 kHz	0.36 mV/V	
	(1 to 20) kHz	0.48 mV/V	
	(20 to 50) kHz	1.3 mV/V	
	(50 to 100) kHz	5.9 mV/V	
	(100 to 300) kHz	46 mV/V	
	12 mV to 12 V		
	(1 to 40) Hz	0.13 mV/V	
	40 Hz to 1 kHz	0.11 mV/V	
	(1 to 20) kHz	0.22 mV/V	
	(20 to 50) kHz	0.37 mV/V	
	(50 to 100) kHz	0.95 mV/V	
	(100 to 300) kHz	3.6 mV/V	
	(0.3 to 1) MHz	1.2 mV/V	
	(1 to 2) MHz	17 mV/V	
	(12 to 120) V		
	(1 to 40) Hz	0.28 mV/V	
	40 Hz to 1 kHz	0.26 mV/V	
	(1 to 20) kHz	0.26 mV/V	
	(20 to 50) kHz	0.43 mV/V	
	(50 to 100) kHz	1.4 mV/V	
	(100 to 300) kHz	4.7 mV/V	
	(0.3 to 1) MHz	17 mV/V	
	(120 to 700) V		
	(1 to 40) Hz	0.53 mV/V	
	40 Hz to 1 kHz	0.5 mV/V	
	(1 to 20) kHz	0.73 mV/V	
	(20 to 50) kHz	1.4 mV/V	
	(50 to 100) kHz	3.5 mV/V	

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
AC Voltage – Measure	2.2 mV		Comparison to Fluke 5790B AC Measurement Standard
	(10 to 20) Hz	0.14 % of reading + 1 μ V	
	(20 to 40) Hz	0.067 % of reading + 1 μ V	
	40 Hz to 20 kHz	0.045 % of reading + 1 μ V	
	(20 to 50) kHz	0.072 % of reading + 1.6 μ V	
	(50 to 100) kHz	0.098 % of reading + 1.9 μ V	
	(100 to 300) kHz	0.18 % of reading + 3.1 μ V	
	(300 to 500) kHz	0.2 % of reading + 6.2 μ V	
	500 kHz to 1 MHz	0.27 % of reading + 6.2 μ V	
	7 mV		
	(10 to 20) Hz	0.067 % of reading + 1 μ V	
	(20 to 40) Hz	0.032 % of reading + 1 μ V	
	40 Hz to 20 kHz	0.021 % of reading + 1 μ V	
	(20 to 50) kHz	0.033 % of reading + 1.6 μ V	
	(50 to 100) kHz	0.05 % of reading + 1.9 μ V	
	(100 to 300) kHz	0.094 % of reading + 3.1 μ V	
	(300 to 500) kHz	0.11 % of reading + 6.2 μ V	
	500 kHz to 1 MHz	0.28 % of reading + 6.2 μ V	
	22 mV		
	(10 to 20) Hz	0.23 % of reading + 1 μ V	
	(20 to 40) Hz	0.015 % of reading + 1 μ V	
	40 Hz to 20 kHz	0.009 % of reading + 1 μ V	
	(20 to 50) kHz	0.016 % of reading + 1.6 μ V	
	(50 to 100) kHz	0.024 % of reading + 1.9 μ V	
	(100 to 300) kHz	0.064 % of reading + 3.1 μ V	
	(300 to 500) kHz	0.078 % of reading + 6.2 μ V	
	500 kHz to 1 MHz	0.2 % of reading + 6.2 μ V	
	70 mV		
	(10 to 20) Hz	0.019 % of reading + 1.2 μ V	
	(20 to 40) Hz	0.01 % of reading + 1.2 μ V	
	40 Hz to 20 kHz	0.005 % of reading + 1.2 μ V	
	(20 to 50) kHz	0.01 % of reading + 1.6 μ V	
	(50 to 100) kHz	0.02 % of reading + 1.9 μ V	
	(100 to 300) kHz	0.041 % of reading + 3.1 μ V	
	(300 to 500) kHz	0.053 % of reading + 6.2 μ V	
	500 kHz to 1 MHz	0.01 % of reading + 6.2 μ V	

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
AC Voltage – Measure	0.22 V		Comparison to Fluke 5790B AC Measurement Standard
	(10 to 20) Hz	0.017 % of reading + 1.2 μ V	
	(20 to 40) Hz	0.007 % of reading + 1.2 μ V	
	40 Hz to 20 kHz	0.003 % of reading + 1.2 μ V	
	(20 to 50) kHz	0.006 % of reading + 1.6 μ V	
	(50 to 100) kHz	0.012 % of reading + 1.9 μ V	
	(100 to 300) kHz	0.022 % of reading + 3.1 μ V	
	(300 to 500) kHz	0.031 % of reading + 6.2 μ V	
	500 kHz to 1 MHz	0.094 % of reading + 6.2 μ V	
	0.7 V		
	(10 to 20) Hz	0.016 % of reading + 1.2 μ V	
	(20 to 40) Hz	0.006 % of reading + 1.2 μ V	
	40 Hz to 20 kHz	0.003 % of reading + 1.2 μ V	
	(20 to 50) kHz	0.004 % of reading + 1.6 μ V	
	(50 to 100) kHz	0.006 % of reading + 1.9 μ V	
	(100 to 300) kHz	0.014 % of reading + 3.1 μ V	
	(300 to 500) kHz	0.023 % of reading + 6.2 μ V	
	500 kHz to 1 MHz	0.076 % of reading + 6.2 μ V	
	2.2 V		
	(10 to 20) Hz	0.016 % of reading	
	(20 to 40) Hz	0.006 % of reading	
	40 Hz to 20 kHz	0.002 % of reading	
	(20 to 50) kHz	0.004 % of reading	
	(50 to 100) kHz	0.006 % of reading	
	(100 to 300) kHz	0.016 % of reading	
	(300 to 500) kHz	0.024 % of reading	
	500 kHz to 1 MHz	0.094 % of reading	
	7 V		
	(10 to 20) Hz	0.016 % of reading	
	(20 to 40) Hz	0.006 % of reading	
	40 Hz to 20 kHz	0.002 % of reading	
	(20 to 50) kHz	0.004 % of reading	
	(50 to 100) kHz	0.006 % of reading	
	(100 to 300) kHz	0.016 % of reading	
	(300 to 500) kHz	0.024 % of reading	
	500 kHz to 1 MHz	0.094 % of reading	

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
AC Voltage – Measure	22 V		Comparison to Fluke 5790B AC Measurement Standard
	(10 to 20) Hz	0.016 % of reading	
	(20 to 40) Hz	0.005 % of reading	
	40 Hz to 20 kHz	0.002 % of reading	
	(20 to 50) kHz	0.004 % of reading	
	(50 to 100) kHz	0.007 % of reading	
	(100 to 300) kHz	0.015 % of reading	
	(300 to 500) kHz	0.032 % of reading	
	500 kHz to 1 MHz	0.093 % of reading	
	70 V		
	(10 to 20) Hz	0.016 % of reading	
	(20 to 40) Hz	0.006 % of reading	
	40 Hz to 20 kHz	0.003 % of reading	
	(20 to 50) kHz	0.005 % of reading	
	(50 to 100) kHz	0.009 % of reading	
	(100 to 300) kHz	0.017 % of reading	
	(300 to 500) kHz	0.04 % of reading	
	500 kHz to 1 MHz	0.12 % of reading	
	220 V		
	(10 to 20) Hz	0.016 % of reading	
	(20 to 40) Hz	0.006 % of reading	
	40 Hz to 20 kHz	0.003 % of reading	
	(20 to 50) kHz	0.006 % of reading	
	(50 to 100) kHz	0.009 % of reading	
	(100 to 300) kHz	0.02 % of reading	
	(300 to 500) kHz	0.054 % of reading	
	700 V		
	(10 to 20) Hz	0.016 % of reading	
	(20 to 40) Hz	0.009 % of reading	
	40 Hz to 20 kHz	0.004 % of reading	
	(20 to 50) kHz	0.012 % of reading	
	(50 to 100) kHz	0.066 % of reading	
	1 000 V		
	(10 to 20) Hz	0.015 % of reading	
	(20 to 40) Hz	0.009 % of reading	
	40 Hz to 20 kHz	0.003 % of reading	
	(20 to 50) kHz	0.012 % of reading	
	(50 to 100) kHz	0.066 % of reading	

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
AC High Voltage – Source/Measure ¹	(1 to 60) kV 60 Hz	3.8 mV/V	Comparison to Ross Engineering VD60-6.2Y-A-LB-AL High Voltage Divider, Keysight 3458A 8.5 Digit Multimeter
AC Current – Source ¹	(29 to 329.99) μ A (10 to 20) Hz (20 to 45) Hz 45 Hz to 1 kHz (1 to 5) kHz (5 to 10) kHz (10 to 30) kHz (0.33 to 3.299 99) mA (10 to 20) Hz (20 to 45) Hz 45 Hz to 1 kHz (1 to 5) kHz (5 to 10) kHz (10 to 30) kHz (3.3 to 32.999 9) mA (10 to 20) Hz (20 to 45) Hz 45 Hz to 1 kHz (1 to 5) kHz (5 to 10) kHz (10 to 30) kHz (33 to 329.999) mA (10 to 20) Hz (20 to 45) Hz 45 Hz to 1 kHz (1 to 5) kHz (5 to 10) kHz (10 to 30) kHz (0.33 to 1.099 99) A (10 to 45) Hz 45 Hz to 1 kHz (1 to 5) kHz (5 to 10) kHz	1.6 nA/ μ A + 78 nA 1.2 nA/ μ A + 78 nA 0.97 nA/ μ A + 78 nA 2.3 nA/ μ A + 0.12 μ A 6.4 nA/ μ A + 0.16 μ A 12 nA/ μ A + 0.31 μ A 1.6 μ A/mA + 0.12 μ A 0.97 μ A/mA + 0.12 μ A 0.79 μ A/mA + 78 nA 1.5 μ A/mA + 0.16 μ A 3.9 μ A/mA + 0.23 μ A 7.9 μ A/mA + 0.47 μ A 1.4 μ A/mA + 1.6 μ A 0.7 μ A/mA + 1.6 μ A 0.3 μ A/mA + 0.16 μ A 0.64 μ A/mA + 0.16 μ A 1.5 μ A/mA + 2.3 μ A 3 μ A/mA + 3.1 μ A 1.4 μ A/mA + 16 μ A 0.7 μ A/mA + 16 μ A 0.33 μ A/mA + 16 μ A 0.79 μ A/mA + 39 μ A 1.6 μ A/mA + 78 μ A 3.3 μ A/mA + 0.16 mA 0.11 mA/A + 78 μ A 0.11 mA/A + 78 μ A 0.16 mA/A + 0.78 mA 0.4 mA/A + 3.9 mA	Comparison to Fluke 5522A Multiproduct Calibrator

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
AC Current – Source ¹	(1.1 to 2.999 99) A (10 to 45) Hz 45 Hz to 1 kHz (1 to 5) kHz (5 to 10) kHz (3 to 10.9999) A (10 to 45) Hz 45 Hz to 1 kHz (1 to 5) kHz (3 to 10.9999) A (10 to 45) Hz 45 Hz to 1 kHz (1 to 5) kHz (11 to 20.5) A (10 to 45) Hz 45 Hz to 1 kHz (1 to 5) kHz	1.4 mA/A + 78 μ A 0.53 mA/A + 78 μ A 4.7 mA/A + 0.78 mA 19 mA/A + 3.9 mA 1 mA/A + 1.6 mA 1.2 mA/A + 1.6 mA 23 mA/A + 1.6 mA 1 mA/A + 1.6 mA 1.2 mA/A + 1.6 mA 23 mA/A + 1.6 mA 1.8 mA/A + 3.9 mA 1.9 mA/A + 3.9 mA 23 mA/A + 3.9 mA	Comparison to Fluke 5522A Multiproduct Calibrator
AC Current – Source ¹	(20 to 1) kHz 100 Hz to 1 kHz	12 mA/A	Comparison to Transmille 4010A Multiproduct Calibrator, Transmille EA002 2/10/50 Coil Adapter
AC Current – Measure	Up to 330 μ A 10 Hz to 1 kHz 1 kHz to 30 kHz (> 0.33 to 3.29) mA 10 Hz to 1 kHz 1 kHz to 30 kHz (> 3.29 to 32.9 mA) 10 Hz to 1 kHz 1 kHz to 5 kHz 5 kHz to 30 kHz (> 32.9 to 329 mA) 10 Hz to 1 kHz 1 kHz to 5 kHz 5 kHz to 30 kHz > 329 mA to 2.99 A 10 Hz to 1 kHz 1 kHz to 5 kHz 5 kHz to 30 kHz	9 nA 4 nA 32 μ A 12 nA 29 μ A 24 μ A 39 μ A 39 μ A 25 μ A 40 μ A 59 μ A 36 μ A 85 μ A	Comparison to Fluke 5790B AC Measurement Standard, Current Shunts

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
AC Current – Source/Measure ¹	45 Hz to 1 kHz (0.1 to 2) mA (2 to 20) mA (20 to 200) mA (0.2 to 2) A (2 to 20) A (20 to 100) A	4.1 mA/A + 3 nA 1.1 mA/A + 30 nA 1 mA/A + 0.3 µA 1 mA/A + 3 µA 1 mA/A + 30 µA 1 mA/A + 0.15 mA	Comparison to Valhalla 2575A Current Shunt, Keysight 3458A 8.5 Digit Multimeter, Current Source
DC Power – Source ¹ 33 mV to 1 020 V	0.33 mA to 2.9999 A 11 µW to 3.06 kW	0.018 % of reading	Comparison to Fluke Multiproduct Calibrator
33 mV to 1 020 V	(3 to 20.5) A 0.1 W to 20.9 kW	0.054 % of reading	
AC Power – Source ¹ 33 mV to 1 020 V (45 to 65) Hz Power Factor: PF=1	(3 to 20.5) A 0.11 mW to 20.9 kW	0.11 % of reading	Comparison to Fluke Multiproduct Calibrator
Capacitance – Source ¹ (Simulated)			
10 Hz to 10 kHz	(220 to 399.9) pF	0.55 % of reading + 7.8 pF	
10 Hz to 10 kHz	(0.4 to 1.099 9) nF	0.42 % of reading + 10 pF	
10 Hz to 3 kHz	(1.1 to 3.299 9) nF	0.39 % of reading + 10 pF	
10 Hz to 1 kHz	(3.3 to 10.999 9) nF	0.2 % of reading + 10 pF	
10 Hz to 1 kHz	(11 to 32.999 9) nF	0.2 % of reading + 8 pF	
10 Hz to 1 kHz	(33 to 109.999) nF	0.2 % of reading + 8 pF	
10 Hz to 1 kHz	(110 to 329.999) nF	0.27 % of reading + 0.23 nF	
(10 to 600) Hz	(0.33 to 1.099 99) µF	0.21 % of reading + 0.78 nF	
(10 to 300) Hz	(1.1 to 3.299 99) µF	0.2 % of reading + 2.3 nF	
(10 to 150) Hz	(3.3 to 10.999 9) µF	0.21 % of reading + 7.8 nF	
(10 to 120) Hz	(11 to 32.999 9) µF	0.3 % of reading + 23 nF	
(10 to 80) Hz	(33 to 109.999) µF	0.35 % of reading + 78 nF	
(DC to 50) Hz	(110 to 329.999) µF	0.36 % of reading + 0.23 µF	
(DC to 20) Hz	(0.33 to 1.099 99) mF	0.36 % of reading + 0.78 µF	
(DC to 6) Hz	(1.1 to 3.299 99) mF	0.36 % of reading + 2.3 µF	
(DC to 2) Hz	(3.3 to 10.999 9) mF	0.35 % of reading + 7.8 µF	
(DC to 0.6) Hz	(11 to 32.999 9) mF	0.58 % of reading + 23 µF	
(DC to 0.2) Hz	(33 to 110) mF	0.85 % of reading + 77 µF	

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Capacitance – Source ^{1,4} (Fixed Artifact)	1 kHz 1 nF 2 nF 5 nF 10 nF 100 nF 1 μ F 10 μ F	0.42 % of reading + 10 pF 0.39 % of reading + 10 pF 0.2 % of reading + 10 pF 0.2 % of reading + 80 pF 0.2 % of reading + 80 pF 0.27 % of reading + 0.23 nF 0.21 % of reading + 0.78 nF	Comparison to Transmille 4010 Multiproduct Calibrator
Capacitance – Measure ¹	12 Hz to 100 kHz 1 pF to 6.4 nF (6.4 to 100) nF (0.1 to 1.6) μ F (1.6 to 100) μ F	0.12 % of reading 0.38 % of reading 0.81 % of reading 0.57 % of reading	Comparison to General Radio 1689M RLC Bridge
Capacitance – Measure ¹	DC 200 μ F to 0.11 F	0.023 % of reading	Comparison to Fluke 5700A Multiproduct Calibrator, Keysight 3458A 8.5 Digit Multimeter; $\Delta V/\Delta T$ Method
Capacitance – Measure ¹	1 kHz 1 pF to 1 μ F	0.000 9 % of reading	Comparison to Andeen-Hagerling 2500A Capacitance Bridge
Inductance – Source/Measure ¹ (Variable Artifact)	100 Hz to 1 kHz 1 mH to 11.11 H	0.27 % of reading	Comparison to General Radio 1689M RLC Bridge, General Radio 1490D Decade Inductor
DC Resistance – Source ¹ (Simulated)	(0 to 11) Ω (11 to 33) Ω (33 to 110) Ω (110 to 330) Ω (0.33 to 1.1) k Ω (1.1 to 3.3) k Ω (3.3 to 11) k Ω (11 to 33) k Ω (33 to 110) k Ω (110 to 330) k Ω	33 $\mu\Omega/\Omega$ + 0.78 m Ω 24 $\mu\Omega/\Omega$ + 1.2 m Ω 22 $\mu\Omega/\Omega$ + 1.1 m Ω 22 $\mu\Omega/\Omega$ + 1.6 m Ω 23 $\mu\Omega/\Omega$ + 1.6 $\mu\Omega$ 23 m Ω/Ω + 16 m Ω 23 m Ω/Ω + 16 m Ω 22 m Ω/Ω + 0.16 Ω 23 m Ω/Ω + 0.16 Ω 26 m Ω/Ω + 1.6 Ω	Comparison to Fluke 5522A Multiproduct Calibrator

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
DC Resistance – Source ¹ (Simulated)	(0.33 to 1.1) MΩ (1.1 to 3.3) MΩ (3.3 to 11) MΩ (11 to 33) MΩ (33 to 110) MΩ (110 to 330) MΩ (330 to 1 100) MΩ	25 mΩ/Ω + 1.6 Ω 48 mΩ/Ω + 23 Ω 0.23 Ω/Ω + 39 Ω 0.2 Ω/Ω + 1.9 kΩ 0.4 Ω/Ω + 2.3 kΩ 2.3 Ω/kΩ + 78 kΩ 12 Ω/kΩ + 0.39 MΩ	Comparison to Fluke 5522A Multiproduct Calibrator
DC Resistance – Source ¹ (Simulated-Fixed)	0 Ω 1.9 Ω 10 Ω 19 Ω 100 Ω 190 Ω 1 kΩ 1.9 kΩ 10 kΩ 19 kΩ 100 kΩ 190 kΩ 1 MΩ 1.9 MΩ 10 MΩ 19 MΩ 100 MΩ	97 μΩ 0.18 mΩ 0.3 mΩ 0.55 mΩ 2 mΩ 3.4 mΩ 16 mΩ 30 mΩ 0.16 Ω 0.28 Ω 1.7 Ω 3.2 Ω 24 Ω 57 Ω 0.18 kΩ 3.5 kΩ 19 kΩ	Comparison to Fluke 5700A Multiproduct Calibrator
DC Resistance – Source ⁴ (Fixed Artifact)	10 mΩ 1 Ω 10 Ω 100 Ω 1 kΩ 10 kΩ 10 MΩ 1 GΩ 1 TΩ	70 μΩ 8.9 μΩ 5.1 μΩ 0.37 mΩ 6.1 mΩ 62 mΩ 3.3 mΩ 0.025 % of output 0.08 % of output	Comparison to Low Thermal Keithley Standard Resistors
DC Resistance – Measure ¹	Up to 12 Ω (12 to 120) Ω (0.12 to 1.2) kΩ (1.2 to 12) kΩ (1.2 to 120) kΩ (0.12 to 1.2) MΩ (1.2 to 12) MΩ (12 to 120) MΩ (0.12 to 1.2) GΩ	19 μΩ/ Ω + 50 μΩ 15 μΩ/ Ω + 0.5 mΩ 13 μΩ/ Ω + 0.5 mΩ 12 μΩ/ Ω + 5 mΩ 13 μΩ/ Ω + 50 μΩ 24 μΩ/ Ω + 2 Ω 65 μΩ/ Ω + 100 Ω 0.58 mΩ/ Ω + 1 kΩ 5.8 mΩ/ Ω + 10 kΩ	Comparison to Keysight 3458A 8.5 Digit Multimeter

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
DC Resistance – Measure ¹	10 mΩ to 1 Ω	73 μΩ/Ω	Comparison to Keysight 34420A 7.5 Digit NanoVolt/Micro-Ohm Meter
DC Resistance – Measure	12 MΩ to 1.1 GΩ	0.007 % of reading	Comparison to Fluke 5700A Multiproduct Calibrator, HP 3458A 8.5 Digit Multimeter
AC Resistance – Source/Measure ¹	1 kHz 1 Ω to 100 kΩ	0.39 mΩ/Ω	Comparison to General Radio 1689M RLC Bridge, HP 16074A Standard Set
Oscilloscopes ^{1,2}			
DC Voltage into 50 Ω into 1 MΩ	(-6 to 6) V (-130 to 130) V	0.25 % of reading + 40 μV 0.05 % of reading + 40 μV	
Square Wave into 50 Ω into 1 MΩ	-1 mVp-p to 6.6 V p-p -1 mVp-p to 130 V p-p	0.25 % of reading + 40 μV 0.1 % of reading + 40 μV	
Time Markers into 50 Ω	1 ns to 20 ms 50 ms to 5 s	2.5 μs/s (25 + 1 000t) μs/s	
Leveled Sine Wave Frequency	50 kHz to 1.1 GHz	0.25 μHz/Hz	
Flatness			
50 kHz (reference)	5 mVp-p to 5.5 Vp-p	2 % of reading + 0.3 mV	
50 kHz to 100 MHz	5 mVp-p to 5.5 Vp-p	3.5 % of reading + 0.3 mV	
(100 to 300) MHz	5 mVp-p to 5.5 Vp-p	4 % of reading + 0.3 mV	
(300 to 600) MHz	5 mVp-p to 5.5 Vp-p	6 % of reading + 0.3 mV	
(0.6 to 1.1) GHz	5 mVp-p to 3.5 Vp-p	7 % of reading + 0.3 mV	

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Oscilloscopes ^{1,2} Edge Characteristics into 50 Ω Rise Time Amplitude Frequency Wave Generator Amplitude (Square, Sine, Triangle) into 50 Ω into 1 M Ω Frequency Input Resistance Measurement into 50 Ω into 1 M Ω Input Capacitance Measurement into 1 M Ω	≤ 300 ps 5 mV to 2.5 V 900 Hz to 11 MHz 1.8 mV to 2.5 Vp-p 1.8 mV to 55 Vp-p 10 Hz to 100 kHz (40 to 60) Ω 500 k Ω to 1.5 M Ω (5 to 50) pF	+ 0 ps / - 100 ps 2 % of reading + 0.2 mV 2.5 μ Hz/Hz 30 mV/V + 0.1 mV 30 mV/V + 0.1 mV 25 μ Hz/Hz + 15 mHz 0.1 % of reading 0.1 % of reading 5 % of reading + 0.5 pF	Comparison to Fluke 5522A Multiproduct Calibrator
Electrical Simulation of Thermocouple Indicating Devices – Source/Measure ¹	Type B (600 to 800) $^{\circ}$ C (800 to 1 000) $^{\circ}$ C (1 000 to 1 550) $^{\circ}$ C (1 550 to 1 820) $^{\circ}$ C Type C (0 to 150) $^{\circ}$ C (150 to 650) $^{\circ}$ C (650 to 1 000) $^{\circ}$ C (1 000 to 1 800) $^{\circ}$ C (1 800 to 2 316) $^{\circ}$ C Type E (-250 to -100) $^{\circ}$ C (-100 to -25) $^{\circ}$ C (-25 to 350) $^{\circ}$ C (350 to 650) $^{\circ}$ C (650 to 1 000) $^{\circ}$ C	0.34 $^{\circ}$ C 0.27 $^{\circ}$ C 0.23 $^{\circ}$ C 0.26 $^{\circ}$ C 0.23 $^{\circ}$ C 0.2 $^{\circ}$ C 0.24 $^{\circ}$ C 0.39 $^{\circ}$ C 0.65 $^{\circ}$ C 0.39 $^{\circ}$ C 0.13 $^{\circ}$ C 0.11 $^{\circ}$ C 0.13 $^{\circ}$ C 0.17 $^{\circ}$ C	Comparison to Fluke 5522A Multiproduct Calibrator

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Electrical Simulation of Thermocouple Indicating Devices – Source/Measure ¹	Type J		Comparison to Fluke 5522A Multiproduct Calibrator
	(-210 to -100) °C	0.21 °C	
	(-100 to -30) °C	0.13 °C	
	(-30 to 150) °C	0.11 °C	
	(150 to 760) °C	0.14 °C	
	(760 to 1 200) °C	0.18 °C	
	Type K		
	(-200 to -100) °C	0.26 °C	
	(-100 to -25) °C	0.14 °C	
	(-25 to 120) °C	0.13 °C	
	(120 to 1 000) °C	0.2 °C	
	(1 000 to 1 372) °C	0.31 °C	
	Type L		
	(-200 to -100) °C	0.29 °C	
	(-100 to 800) °C	0.2 °C	
	(800 to 900) °C	0.14 °C	
	Type N		
	(-200 to -100) °C	0.31 °C	
	(-100 to -25) °C	0.17 °C	
	(-25 to 120) °C	0.15 °C	
	(120 to 410) °C	0.14 °C	
	(410 to 1 300) °C	0.21 °C	
	Type R		
	(0 to 250) °C	0.44 °C	
	(250 to 400) °C	0.27 °C	
	(400 to 1 000) °C	0.26 °C	
	(1 000 to 1 767) °C	0.31 °C	
	Type S		
	(0 to 250) °C	0.37 °C	
	(250 to 1 000) °C	0.28 °C	
	(1 000 to 1 400) °C	0.29 °C	
	(1 400 to 1 767) °C	0.36 °C	
	Type T		
	(-250 to -150) °C	0.49 °C	
	(-150 to 0) °C	0.19 °C	
	(0 to 120) °C	0.13 °C	
	(120 to 400) °C	0.11 °C	
	Type U		
	(-200 to 0) °C	0.44 °C	
	(0 to 600) °C	0.21 °C	

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Electrical Simulation of RTD Indicating Devices – Source ¹	Pt 385, 100 Ω		Comparison to Fluke 5522A Multiproduct Calibrator
	(-200 to -80) °C	0.04 °C	
	(-80 to 0) °C	0.04 °C	
	(0 to 100) °C	0.05 °C	
	(100 to 300) °C	0.07 °C	
	(300 to 400) °C	0.08 °C	
	(400 to 630) °C	0.09 °C	
	(630 to 800) °C	0.18 °C	
	Pt 3926, 100 Ω		
	(-200 to -80) °C	0.04 °C	
	(-80 to 0) °C	0.04 °C	
	(0 to 100) °C	0.05 °C	
	(100 to 300) °C	0.07 °C	
	(300 to 400) °C	0.08 °C	
	(400 to 630) °C	0.09 °C	
	Pt 3916, 100 Ω		
	(-200 to -190) °C	0.19 °C	
	(-190 to -80) °C	0.03 °C	
	(-80 to 0) °C	0.04 °C	
	(0 to 100) °C	0.05 °C	
	(100 to 260) °C	0.05 °C	
	(260 to 300) °C	0.06 °C	
	(300 to 400) °C	0.07 °C	
	(400 to 600) °C	0.08 °C	
	(600 to 630) °C	0.18 °C	
	Pt 385, 200 Ω		
	(-200 to -80) °C	0.03 °C	
	(-80 to 0) °C	0.03 °C	
	(0 to 100) °C	0.03 °C	
	(100 to 260) °C	0.04 °C	
	(260 to 300) °C	0.09 °C	
	(300 to 400) °C	0.1 °C	
	(400 to 600) °C	0.11 °C	
	(600 to 630) °C	0.12 °C	

Electrical – DC/Low Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Electrical Simulation of RTD Indicating Devices – Source ¹	Pt 385, 500 Ω		Comparison to Fluke 5522A Multiproduct Calibrator
	(-200 to -80) $^{\circ}\text{C}$	0.03 $^{\circ}\text{C}$	
	(-80 to 0) $^{\circ}\text{C}$	0.04 $^{\circ}\text{C}$	
	(0 to 100) $^{\circ}\text{C}$	0.04 $^{\circ}\text{C}$	
	(100 to 260) $^{\circ}\text{C}$	0.05 $^{\circ}\text{C}$	
	(260 to 300) $^{\circ}\text{C}$	0.06 $^{\circ}\text{C}$	
	(300 to 400) $^{\circ}\text{C}$	0.06 $^{\circ}\text{C}$	
	(400 to 600) $^{\circ}\text{C}$	0.07 $^{\circ}\text{C}$	
	(600 to 630) $^{\circ}\text{C}$	0.09 $^{\circ}\text{C}$	
	Pt 385, 1 000 Ω		
	(-200 to -80) $^{\circ}\text{C}$	0.02 $^{\circ}\text{C}$	
	(-80 to 0) $^{\circ}\text{C}$	0.02 $^{\circ}\text{C}$	
	(0 to 100) $^{\circ}\text{C}$	0.03 $^{\circ}\text{C}$	
	(100 to 260) $^{\circ}\text{C}$	0.04 $^{\circ}\text{C}$	
	(260 to 300) $^{\circ}\text{C}$	0.05 $^{\circ}\text{C}$	
	(300 to 400) $^{\circ}\text{C}$	0.05 $^{\circ}\text{C}$	
	(400 to 600) $^{\circ}\text{C}$	0.05 $^{\circ}\text{C}$	
	(600 to 630) $^{\circ}\text{C}$	0.18 $^{\circ}\text{C}$	
	Ni 385, 120 Ω		
	(-80 to 0) $^{\circ}\text{C}$	0.06 $^{\circ}\text{C}$	
	(0 to 100) $^{\circ}\text{C}$	0.06 $^{\circ}\text{C}$	
	(100 to 260) $^{\circ}\text{C}$	0.01 $^{\circ}\text{C}$	
	Cu 427, 10 Ω		
	(-100 to 260) $^{\circ}\text{C}$	0.31 $^{\circ}\text{C}$	
Phase Measurement ¹ (0 to 360) $^{\circ}$	(0.329 to 360) V		Comparison to Krohn-Hite 6620A Phase Meter
	Up to 10 Hz	0.12 $^{\circ}$	
	> 10 Hz to 50 kHz	0.06 $^{\circ}$	
	> 50 kHz to 10 MHz	0.4 $^{\circ}$	

Electrical – RF/Microwave

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
RF/Microwave Power – Source/Measure ¹	100 kHz to 4.2 GHz (-30 to 20) dBm	1.6 % of reading	Comparison to HP 8482A Power Sensor, Power Meter

Electrical – RF/Microwave

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
RF/Microwave Power – Source/Measure ¹	10 MHz to 26.5 GHz (-30 to 20) dBm	1.8 % of reading	Comparison to HP 8485A Power Sensor, Power Meter
RF/Microwave Power – Source/Measure ¹	10 MHz to 18 GHz (-60 to 20) dBm	0.97 % of reading	Comparison to Keysight E9300A Power Sensor, Power Meter
RF/Microwave Power – Source/Measure ¹	9 kHz to 6 GHz (-60 to 20) dBm	0.93 % of reading	Comparison to Keysight E9304A Power Sensor, Power Meter
RF/Microwave Power – Source/Measure ¹	10 MHz to 18 GHz (-30 to 0) dBm	0.7 % of reading	Comparison to HP 8478B Power Sensor, Power Meter
RF/Microwave Power – Source/Measure ¹	25 MHz to 1 GHz (1 to 110) W	0.3 W	Comparison to R&S NAP-Z4 Power Head/Sensor, Power Meter
RF/Microwave Power – Source/Measure ¹	10 MHz to 18 GHz (-70 to -20) dBm (-20 to 20) dBm	1.4 % of reading 1.1 % of reading	Comparison to Keysight 8481D Power Sensor, Keysight E4418B Power Meter, Signal Generator
Attenuation – Measure or Tuned RF Power 2.5 MHz to 18 GHz	(0 to 10) dB (-10 to 0) dB (-20 to -10) dB (-30 to -20) dB (-40 to -30) dB (-50 to -40) dB (-60 to -50) dB	0.15 dB 0.15 dB 0.15 dB 0.15 dB 0.15 dB 0.15 dB 0.17 dB	Comparison to Keysight 8902A Measuring Receiver, Keysight 11793A Microwave Converter
Attenuation – Measure or Tuned RF Power 2.5 MHz to 18 GHz	(-70 to -60) dB (-80 to -70) dB (-90 to -80) dB (-100 to -90) dB (-110 to -100) dB (-120 to -110) dB (-127 to -120) dB	0.17 dB 0.2 dB 0.22 dB 0.22 dB 0.33 dB 0.43 dB 0.43 dB	Comparison to Keysight 8902A Measuring Receiver, Keysight 11793A Microwave Converter

Electrical – RF/Microwave

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Amplitude Modulation – Measure 150 kHz to 10 MHz 10 MHz to 1.3 GHz 10 MHz to 1.3 GHz (1.3 to 26.5) GHz (1.3 to 26.5) GHz	Rate: 50 Hz to 10 kHz Depths: (5 to 99) % Rate: 50 Hz to 50 kHz Depths: (5 to 99) % Rate: 20 Hz to 100 kHz Depths: (5 to 99) % Rate: 20 Hz to 100 kHz Depths: (5 to 99) % Rate: 20 Hz to 100 kHz Depths: (5 to 99) %	2.3 % of reading 1.2 % of reading 3.5 % of reading 1.8 % of reading 3.5 % of reading	Comparison to Agilent 8902A Measuring Receiver
Frequency Modulation – Measure Carrier Frequency: 250 kHz to 10 MHz 10 MHz to 1.3 GHz	Rate: 20 Hz to 10 kHz Dev.: ≤ 40 kHz peak Rate: 20 Hz to 200 kHz Dev.: ≤ 400 kHz peak	2.3 % of reading 5.8 % of reading	Comparison to Keysight 8902A Measuring Receiver
Frequency Modulation – Measure Carrier Frequency: (1.3 to 26.5) GHz	Rate: 20 Hz to 200 kHz Dev.: ≤ 400 kHz peak	5.8 % of reading	Comparison to Keysight 8902A Measuring Receiver
Phase Modulation – Measure 10 MHz to 1.3 GHz 1.3 GHz to 26.5 GHz	Rate: 200 Hz 20 kHz Dev.: .1 to 400 rad Rate: 200 Hz 20 kHz Dev.: $> .1$ to 400 rad	3.5 % of reading 4.6 % of reading	Comparison to Agilent 8902A Measuring Receiver, Keysight 11722A / 11792A Sensor Modules
Harmonic Distortion	9 kHz to 6.5 GHz (6.5 to 26.5) GHz (26.5 to 40) GHz	1.7 dB 2.6 dB 3.4 dB	Comparison to Keysight 8565E Spectrum Analyzer
Total Harmonic Distortion	(-80 to 0) dBm 20 Hz to 20 kHz (20 to 100) kHz	1.2 dB 2.3 dB	Comparison to HP 8903B Distortion Analyzer

Length – Dimensional Metrology

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Height Gage ^{1,2}	Up to 24 in	$(22 + 13L) \mu\text{in}$	Comparison to Gage Blocks, Height Gage, Repeat-O-Meter
Micrometer ^{1,2,3}	Up to 12 in	$(47 + 4.8L) \mu\text{in}$	Comparison to Gage Blocks
Calipers ^{1,2}	Up to 36 in	$(345 + 5L) \mu\text{in}$	Comparison to Gage Blocks
Caliper – Parallelism ¹	(0.15 to 0.5) in	$8.8 \mu\text{in/in}$	Comparison to Gage Ball
Depth Micrometers ^{1,3}	Up to 6 in	$(30 + 4.9L) \mu\text{in}$	Comparison to Gage Blocks
External Diameter ² Pin Gages, Set Plugs	Up to 12 in	$(4.5 + 5.6L) \mu\text{in}$	Comparison to Universal Length Measuring Machine
Internal Diameter ²	(0.04 to 3) in	$(9.4 + 3.2L) \mu\text{in}$	Comparison to Universal Length Measuring Machine
Length Standards ²	(1 to 8) in	$(5 + 1.8L) \mu\text{in}$	Comparison to Universal Length Measuring Machine, Gage Blocks
Radius Gages ²	(0.031 25 to 1) in	$(291 + 98L) \mu\text{in}$	Comparison to Keyence
Gage Blocks ²	Up to 12 in	$(1.5 + 5.7L) \mu\text{in}$	Comparison to Universal Length Measuring Machine, Master Gage Blocks
Angle Measurement ² Digital Protractors, Levels, Inclinometers	Up to 90°	22" (0.006°)	Comparisons to Sine Bar, Gage Blocks, Surface Plate, Right Angles
Steel Rules, Tape Measure	Up to 80 in	0.002 6 in	Comparison to DRO Linear Recorder
Flatness	Up to 3 in	$4.5 \mu\text{in}$	Comparison to Optical Flat, Monochromatic Light
Dial Indicators ²	(0.1 to 6) in	$(4.5 + 5.6L) \mu\text{in}$	Comparison to P&W Universal Length Measuring Machine

Mass and Mass Related

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Class I Balances ¹			ASTM E617 Class 1 Weights and NIST Handbook 44 utilized for the calibration of the weighing system.
(0.000 01 g resolution)	Up to 100 g	0.29 mg	
(0.000 02 g resolution)	Up to 100 g	0.29 mg	
(0.000 05 g resolution)	Up to 100 g	0.3 mg	
(0.000 1 g resolution)	Up to 200 g	0.6 mg	
(0.000 2 g resolution)	Up to 200 g	0.6 mg	
(0.000 5 g resolution)	Up to 200 g	0.87 mg	
Class II Balances ¹			ASTM E617 Class 1 Weights and NIST Handbook 44 utilized for the calibration of the weighing system.
(0.001 g resolution)	Up to 100 g	1.3 mg	
(0.002 g resolution)	Up to 200 g	2.6 mg	
(0.005 g resolution)	Up to 500 g	6.6 mg	
(0.01 g resolution)	Up to 1 kg	13 mg	
(0.02 g resolution)	Up to 2 kg	29 mg	
(0.05 g resolution)	Up to 5 kg	0.15 g	
(0.1 g resolution)	Up to 10 kg	0.31 g	
(0.2 g resolution)	Up to 20 kg	0.36 g	
Class III Light Capacity Scales ¹			NIST Class F Weights and NIST Handbook 44 utilized for the calibration of the weighing system.
(0.000 5 lb resolution)	Up to 5 lb	0.000 87 lb	
(0.001 lb resolution)	Up to 10 lb	0.001 7 lb	
(0.002 lb resolution)	Up to 20 lb	0.002 6 lb	

Mass and Mass Related

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Class III Light Capacity Scales ¹ (0.005 lb resolution) (0.01 lb resolution) (0.02 lb resolution) (0.05 lb resolution) (0.1 lb resolution)	Up to 50 lb Up to 100 lb Up to 200 lb Up to 500 lb Up to 500 lb	0.008 7 lb 0.018 lb 0.036 lb 0.087 lb 0.14 lb	NIST Class F Weights and NIST Handbook 44 utilized for the calibration of the weighing system.
Force Gages – Tension ¹	(1 to 110) lbf	0.06 lb	Comparison to NIST Class F Weights, Hangers
Durometers – Spring Force Only Types A, B, O, C, D, DO	209.04 gf to 4.079 kgf	0.01 % of reading	Partial verification utilizing Triple Beam Balance and ASTM E617 Class 1 weights per internal procedure.
Vacuum – Measure/Generate ¹	(-14 to 0) psi	0.003 7 psi	Comparison to Additel ADT681-02 Digital Vacuum Gage
Pressure – Source/Measure ¹	(-2 to 2) inH ₂ O	0.002 5 inH ₂ O	Comparison to Additel ADT681-DP2 Digital Compound Gage
Pressure – Source/Measure ¹	(0 to 10) inH ₂ O	0.001 5 inH ₂ O	Comparison to Fluke 700P01 Pressure Module
Pressure – Source/Measure ¹	(-5 to 5) psi	0.004 3 psi	Comparison to Fluke 700PD3 Pressure Module
Pressure – Source/Measure ¹	(0 to 30) psi	0.008 8 psi	Comparison to Additel 681-GP30 Digital Pressure Gage
Pressure – Source/Measure ¹	(0 to 100) psi	0.17 psi	Comparison to Fluke 700G06 Pressure Module
Pressure – Source/Measure ¹	(0 to 500) psi	0.11 psi	Comparison to Additel 681-GP500 Digital Pressure Gage

Mass and Mass Related

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Pressure – Source/Measure ¹	(0 to 1 000) psi	0.66 psi	Comparison to Crystal XP2i-1000 Digital Pressure Gage
Pressure – Source/Measure ¹	(0 to 3 000) psi	1.7 psi	Comparison to GE Druck DPI104-3K Digital Pressure Gage
Pressure – Source/Measure ¹	(0 to 10 000) psi	5.8 psi	Comparison to GE Druck DPI104-10K Digital Pressure Gage
Pressure – Source/Measure ¹	(0 to 30 000) psi	18 psi	Comparison to Additel 681-GP30K Digital Pressure Gage
Pressure – Source/Measure ¹	(> 499 to < 1 104) hPa	0.003 1 % of reading	Comparison to Vaisala PTU200/HMP45 Barometric Pressure Transducer
Torque Indicating Devices ¹	(5 to 200) ozf·in	0.29 % of reading	Comparison to Torque Transducers, Torque Display
	(4 to 50) lbf·in	0.29 % of reading	
	(30 to 400) lbf·in	0.29 % of reading	
	(80 to 1 000) lbf·in	0.3 % of reading	
	(20 to 250) lbf·ft	0.34 % of reading	
	(60 to 600) lbf·ft	0.59 % of reading	
Torque Analyzers, Torque Transducers	(200 to 2 000) lbf·ft	0.59 % of reading	Comparison to Torque Wheels/Arms, Weight Hanger, Master Weights
	(5 to 200) ozf·in	0.044 % of reading	
	(4 to 50) lbf·in	0.044 % of reading	
	(30 to 400) lbf·in	0.044 % of reading	
	(80 to 1 000) lbf·in	0.044 % of reading	
	(20 to 250) lbf·ft	0.054 % of reading	
	(60 to 600) lbf·ft	0.096 % of reading	
	(200 to 2 000) lbf·ft	0.12 % of reading	

Thermodynamic

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Temperature – Generate/Measure ¹	(-25 to 420) °C	0.04 °C	Comparison to Fluke Blackstack Readout, SPRT, Heat Source

Thermodynamic

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Temperature – Generate/Measure ¹	(400 to 1 200) °C	0.32 °C	Comparison to Fluke Blackstack Readout, Type-S Thermocouple Probe, Heat Source
Infrared Thermometers ¹	100 °C 300 °C 500 °C	0.6 °C 0.85 °C 1.2 °C	Comparison to SPRT w/ Fluke 9132A Blackbody Calibrator (flat plate) $\epsilon = 0.95, \lambda = (8 \text{ to } 14) \mu\text{m}$
Humidity – Generate ⁵	25 °C 11.3 %RH 32.78 %RH 57.57 %RH 75.29 %RH	0.27 %RH 0.16 %RH 0.4 %RH 0.12 %RH	Certified Humidity Salts and Reference Thermometer per Journal of Research of the National Bureau of Standards – A. Physics and Chemistry Volume 81 A, No. 1, January/February 1977.
Humidity – Measure ¹	11.3 %RH 33 %RH 75.4 %RH 90 %RH	0.6 %RH 0.72 %RH 0.9 %RH 0.9 %RH	Comparison to Vaisala M170/HMP75 Measurement Indicator with Temp/Humidity Probe

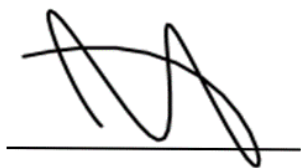
Time and Frequency

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Frequency – Source/Measure	10 Hz to 40 GHz	50 pHz/Hz	Comparison to GPS Disciplined Oscillator, Signal Generators, Universal Counters
Timers, Stopwatches	(2 to 86 400) s	42 ms/d	Comparison to Timometer
Optical Tachometer ²	(1 to 100 000) rpm	0.001 2 % of reading	Comparison to Signal Generator, GPS Disciplined Oscillator, LED

Calibration and Measurement Capability (CMC) is expressed in terms of the measurement parameter, measurement range, expanded uncertainty of measurement and reference standard, method, and/or equipment. The expanded uncertainty of measurement is expressed as the standard uncertainty of the measurement multiplied by a coverage factor of 2 ($k=2$), corresponding to a confidence level of approximately 95%.

Notes:

1. On-site calibration service is available for this parameter, since on-site conditions are typically more variable than those in the laboratory, larger measurement uncertainties are expected on-site than what is reported on the accredited scope.
2. L = length in inches, T = time in seconds; " = arc-second; rpm = revolutions per minute.
3. Resolution is not included on the CMC as the best device may not have been available for repeatability studies/ The Resolution will be add as $0.6R$, where R = resolution, at the time of calculating Measurement Uncertainty (MU) during calibration.
4. These values listed in the Range column are Nominal, but the calibrator will display the actual value. The Expanded Uncertainty of Measurement lists the percentage of output (actual value on the display) plus the floor.
5. The values presented in the Range column are nominal. The actual values will be listed at the time of calibration along with the corresponding Measurement Uncertainty (MU).
6. Unless otherwise specified in the far-right column, the calibration procedure utilized was written internally.
7. This scope is formatted as part of a single document including Certificate of Accreditation No. AC-2548.



Jason Stine, Vice President